

TC74AC390P, TC74AC390F, TC74AC390FN

Dual Decade Counter

The TC74AC390 is an advanced high speed CMOS DUAL DECADE COUNTER fabricated with silicon gate and double-layer metal wiring C²MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

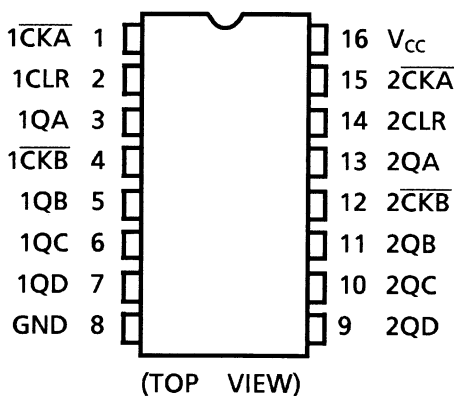
It consists of two independent 4-bit counters, each composed of a divide-by-two and a divide-by-five counter. The divide-by-two counter is incremented on the negative going transition of clock A (\overline{CKA}). The divided-by-five counter is incremented on the negative going transition of clock B (\overline{CKB}). The counter can be cascaded to form decade, bi-quinary, or various combinations up to a divide-by-100 counter. When the CLEAR input is set high, the Q outputs are set to low independent of the clock inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

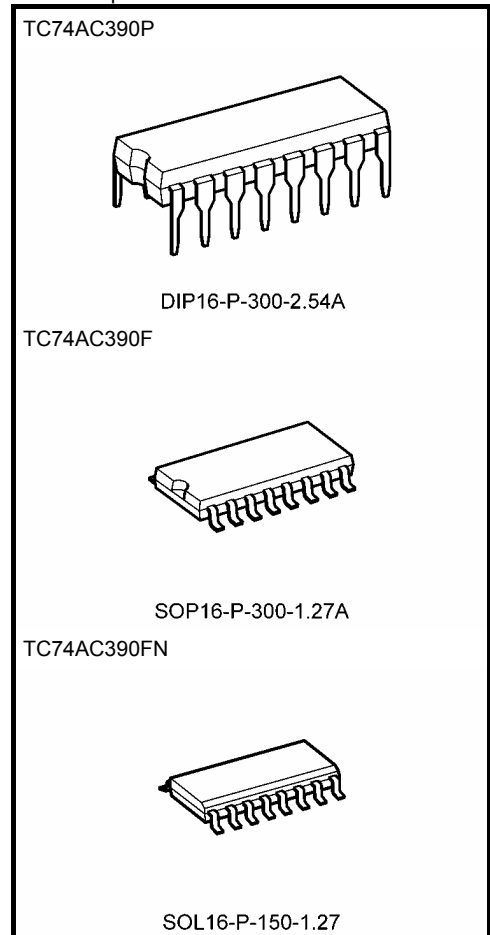
Features

- High speed: $f_{max} = 160$ MHz (typ.) at $V_{CC} = 5$ V
- Low power dissipation: $I_{CC} = 8$ μ A (max) at $T_a = 25^\circ$ C
- High noise immunity: $V_{NIH} = V_{NIL} = 28\%$ V_{CC} (min)
- Symmetrical output impedance: $|I_{OH}| = I_{OL} = 24$ mA (min)
Capability of driving 50 Ω transmission lines.
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range: $V_{CC} (opr) = 2$ to 5.5 V
- Pin and function compatible with 74HC390

Pin Assignment



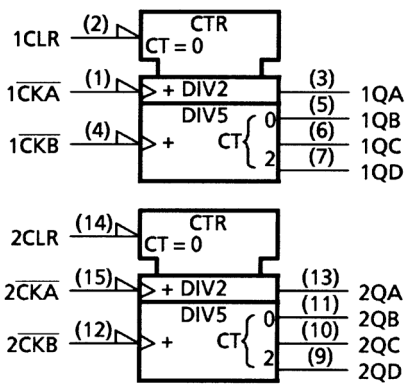
Note: xxxFN (JEDEC SOP) is not available in Japan.



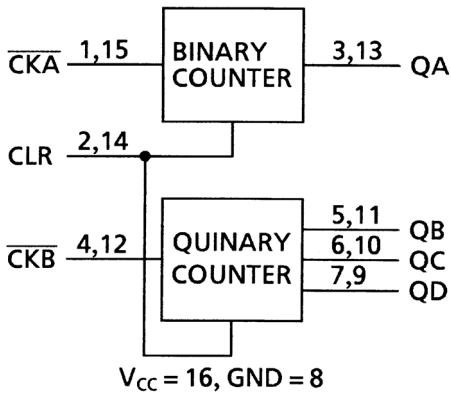
Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

IEC Logic Symbol



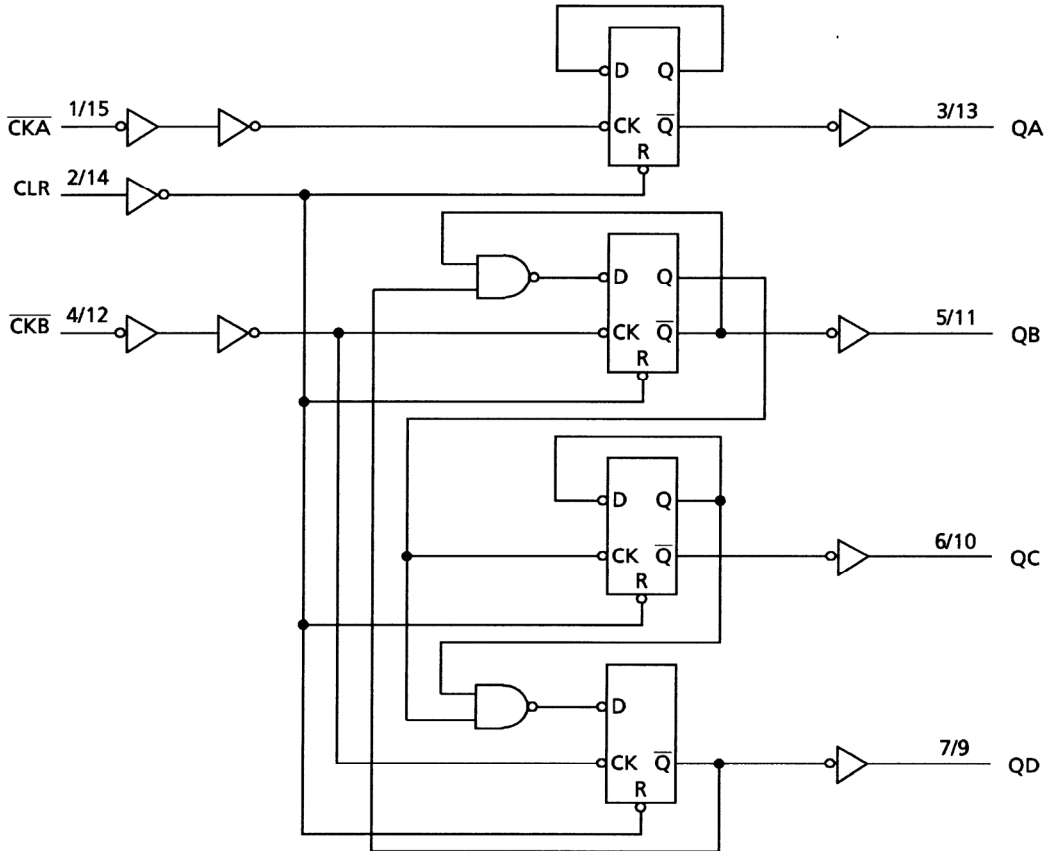
Block Diagram



Truth Table

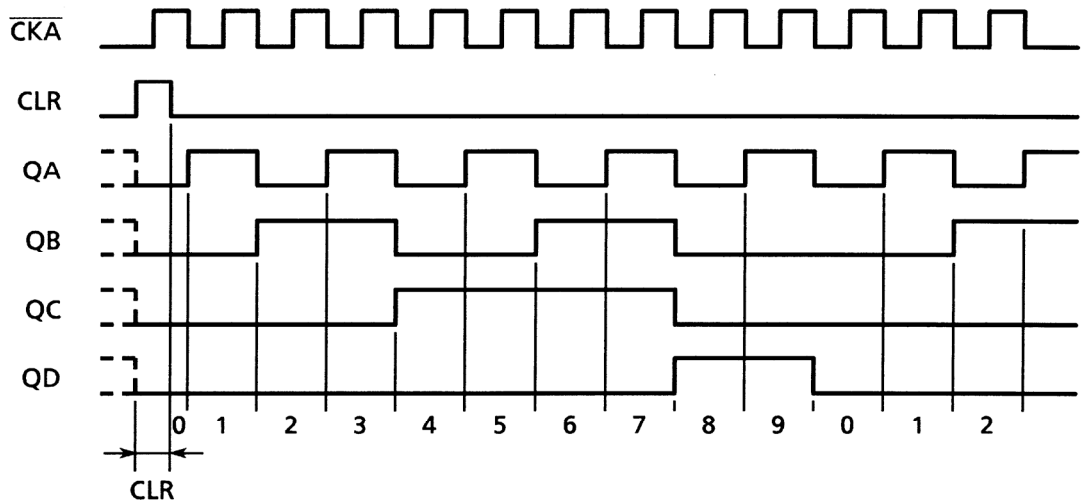
Inputs			Outputs			
\overline{CKA}	\overline{CKB}	CLR	QA	QB	QC	QD
X	X	H	L	L	L	L
\downarrow	X	L	Binary Count Up			
X	\downarrow	L	Quinary Count Up			

System Diagram



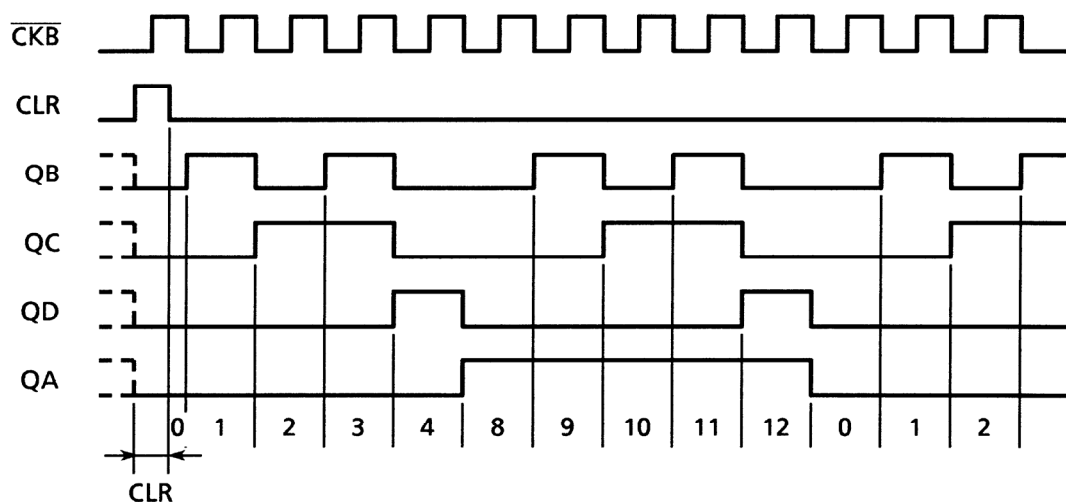
Timing Chart

(1) BCD count sequence (Note)



Note: QA connected to $\overline{\text{CKB}}$

(2) Bi-quinary count sequence (Note)



Note: QD connected to \overline{CKA}

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5 to 7.0	V
DC input voltage	V_{IN}	-0.5 to $V_{CC} + 0.5$	V
DC output voltage	V_{OUT}	-0.5 to $V_{CC} + 0.5$	V
Input diode current	I_{IK}	± 20	mA
Output diode current	I_{OK}	± 50	mA
DC output current	I_{OUT}	± 50	mA
DC V_{CC} /ground current	I_{CC}	± 200	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	-65 to 150	$^{\circ}C$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of $T_a = -40$ to $65^{\circ}C$. From $T_a = 65$ to $85^{\circ}C$ a derating factor of -10 mW/ $^{\circ}C$ should be applied up to 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2.0 to 5.5	V
Input voltage	V_{IN}	0 to V_{CC}	V
Output voltage	V_{OUT}	0 to V_{CC}	V
Operating temperature	T_{opr}	-40 to 85	$^{\circ}C$
Input rise and fall time	dt/dV	0 to 100 ($V_{CC} = 3.3 \pm 0.3$ V) 0 to 20 ($V_{CC} = 5 \pm 0.5$ V)	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit	
				V _{CC} (V)	Min	Typ.	Max	Min		Max
High-level input voltage	V _{IH}	—		2.0	1.50	—	—	1.50	—	V
				3.0	2.10	—	—	2.10	—	
				5.5	3.85	—	—	3.85	—	
Low-level input voltage	V _{IL}	—		2.0	—	—	0.50	—	0.50	V
				3.0	—	—	0.90	—	0.90	
				5.5	—	—	1.65	—	1.65	
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -50 μA	2.0	1.9	2.0	—	1.9	—	V
				3.0	2.9	3.0	—	2.9	—	
			I _{OH} = -4 mA	4.5	4.4	4.5	—	4.4	—	
			I _{OH} = -24 mA	3.0	2.58	—	—	2.48	—	
		I _{OH} = -75 mA (Note)	4.5	3.94	—	—	3.80	—		
			5.5	—	—	—	3.85	—		
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 50 μA	2.0	—	0.0	0.1	—	0.1	V
				3.0	—	0.0	0.1	—	0.1	
				4.5	—	0.0	0.1	—	0.1	
			I _{OL} = 12 mA	3.0	—	—	0.36	—	0.44	
		I _{OL} = 24 mA	4.5	—	—	0.36	—	0.44		
		I _{OL} = 75 mA (Note)	5.5	—	—	—	—	1.65		
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		5.5	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		5.5	—	—	8.0	—	80.0	μA

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

Timing Requirements (input: t_r = t_f = 3 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C	Ta = -40 to 85°C	Unit	
				V _{CC} (V)	Limit		Limit
Minimum pulse width (\overline{CKA} , \overline{CKB})	t _W (H)	—		3.3 ± 0.3	7.0	7.0	ns
	t _W (L)			5.0 ± 0.5	5.0	5.0	
Minimum pulse width (CLR)	t _W (H)	—		3.3 ± 0.3	7.0	7.0	ns
				5.0 ± 0.5	5.0	5.0	
Minimum removal time	t _{rem}	—		3.3 ± 0.3	7.0	7.0	ns
				5.0 ± 0.5	3.5	3.5	

AC Characteristics ($C_L = 50 \text{ pF}$, $R_L = 500 \Omega$, input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition	Ta = 25°C			Ta = -40 to 85°C		Unit	
			V _{CC} (V)	Min	Typ.	Max	Min		Max
Propagation delay time ($\overline{\text{CKA}}$ -QA)	t_{pLH}	—	3.3 ± 0.3	—	8.2	14.0	1.0	16.0	ns
	t_{pHL}		5.0 ± 0.5	—	5.5	8.4	1.0	9.6	
Propagation delay time ($\overline{\text{CKA}}$ -QC)	t_{pLH}	QA connected to $\overline{\text{CKB}}$	3.3 ± 0.3	—	17.0	30.0	1.0	34.0	ns
	t_{pHL}		5.0 ± 0.5	—	10.5	17.5	1.0	20.0	
Propagation delay time ($\overline{\text{CKB}}$ -QB, QD)	t_{pLH}	—	3.3 ± 0.3	—	8.8	14.9	1.0	17.0	ns
	t_{pHL}		5.0 ± 0.5	—	6.0	9.4	1.0	10.7	
Propagation delay time ($\overline{\text{CKB}}$ -QC)	t_{pLH}	—	3.3 ± 0.3	—	11.0	18.8	1.0	21.5	ns
	t_{pHL}		5.0 ± 0.5	—	7.1	11.3	1.0	12.8	
Propagation delay time (CLR-Qn)	t_{pHL}	—	3.3 ± 0.3	—	7.7	12.5	1.0	14.3	ns
			5.0 ± 0.5	—	5.7	8.5	1.0	9.7	
Maximum clock frequency ($\overline{\text{CKA}}$)	f_{max}	—	3.3 ± 0.3	60	120	—	60	—	MHz
			5.0 ± 0.5	100	180	—	100	—	
Maximum clock frequency ($\overline{\text{CKB}}$)	f_{max}	—	3.3 ± 0.3	45	90	—	45	—	MHz
			5.0 ± 0.5	90	140	—	90	—	
Input capacitance	C_{IN}	—	—	5	10	—	10	pF	
Power dissipation capacitance	C_{PD} (Note)	—	—	40	—	—	—	pF	

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

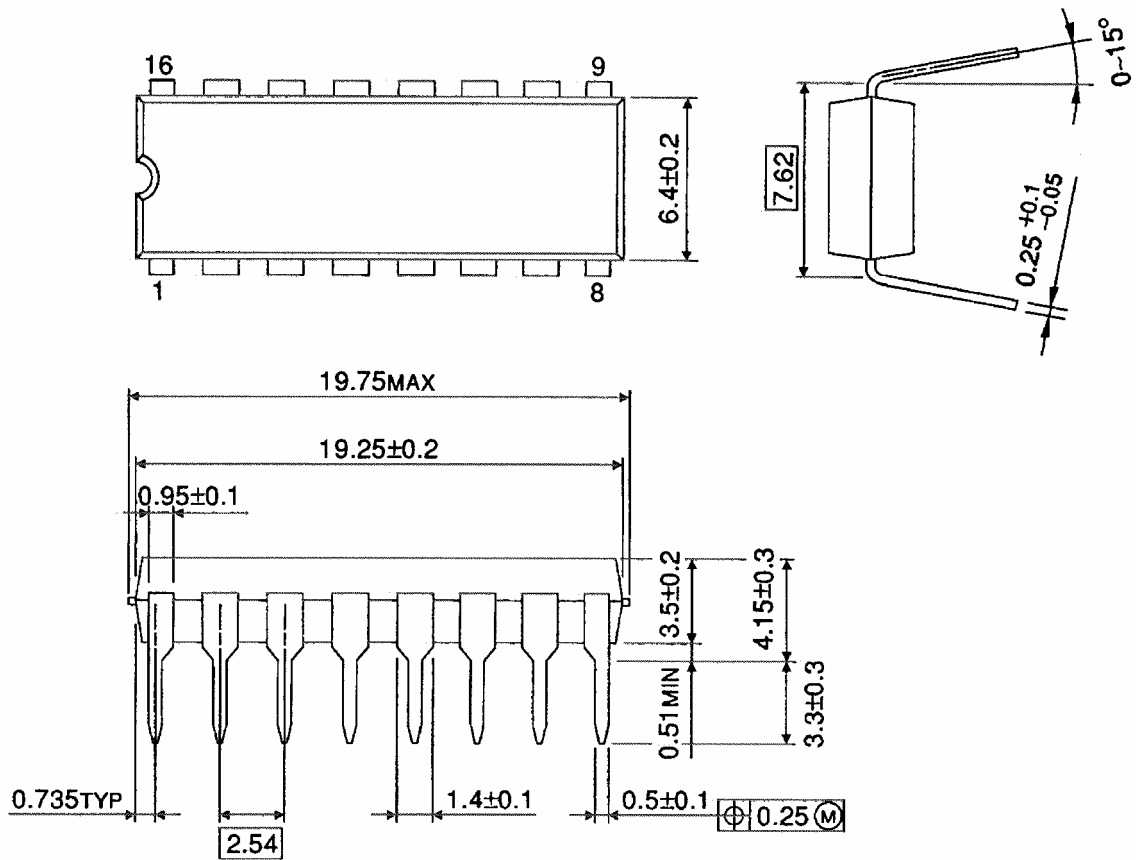
Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2 \text{ (per counter)}$$

Package Dimensions

DIP16-P-300-2.54A

Unit : mm

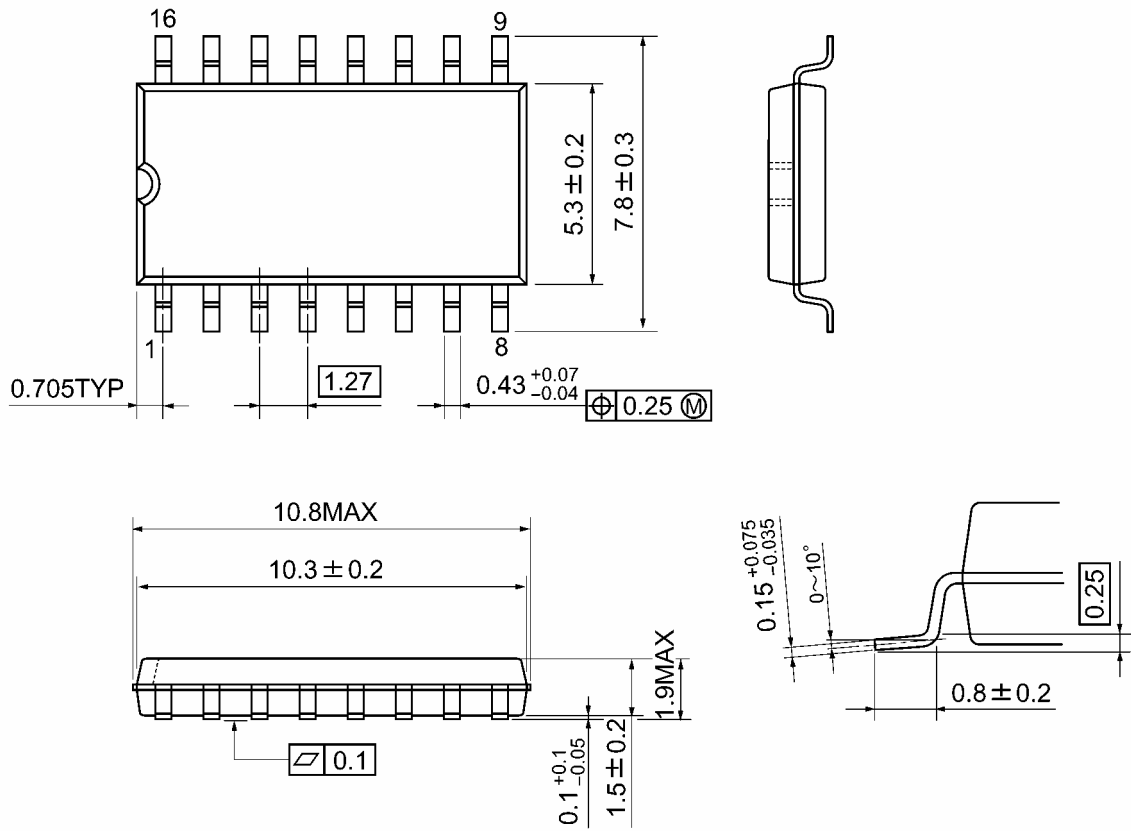


Weight: 1.00 g (typ.)

Package Dimensions

SOP16-P-300-1.27A

Unit: mm

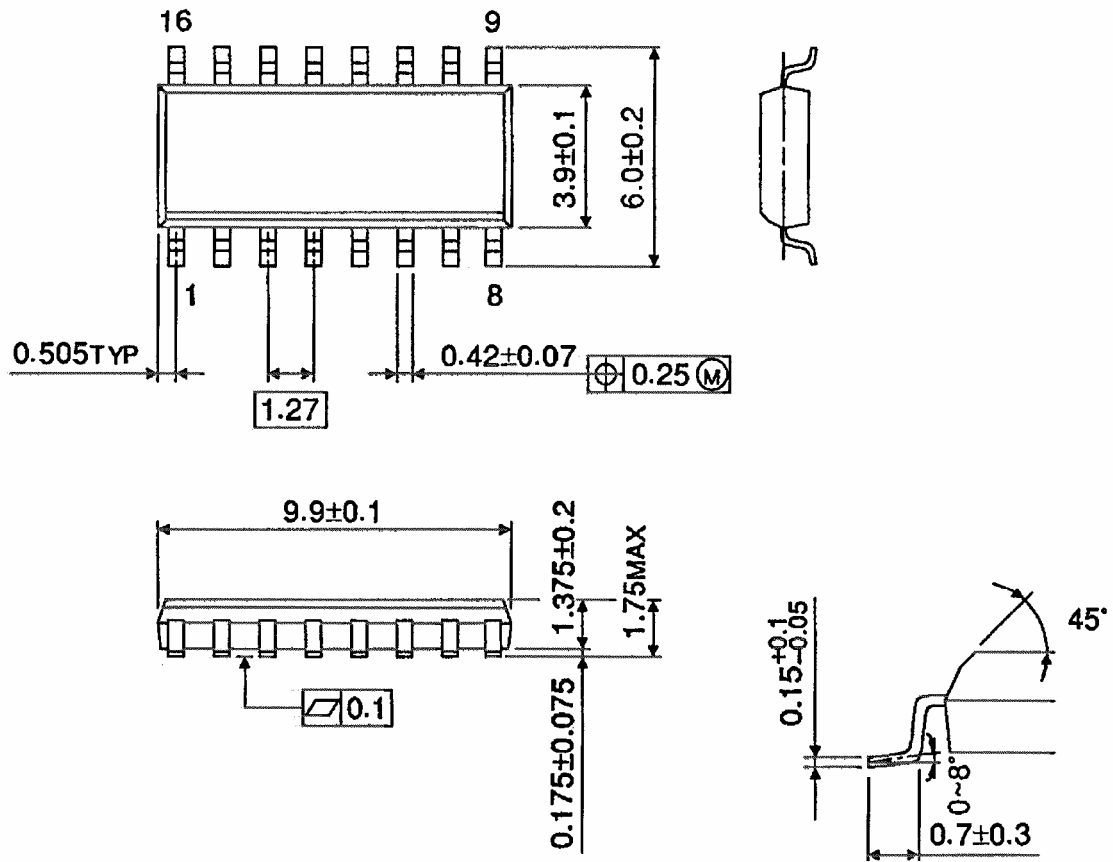


Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL16-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)

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20070701-EN GENERAL

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